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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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Conf. No.:	Not Yet Assigned	§ §	Group Art Unit:	Not Yet Assigned
Appln. No.:	Not Yet Assigned	§ §	Examiner:	Not Yet Assigned
Filing Date:	Herewith	§ §	Attorney Docket No.: 6023-170US (BX2390M)	

Title: METHOD FOR MEASURING THE CONCENTRATION OF WATER IN ARGON, HYDROGEN, NITROGEN AND HELIUM BY MEANS OF IONIZATION MOBILITY SPECTROMETRY

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. §1.97(b)

Enclosed are copies of each of the documents listed on the attached Information Disclosure Citation Form(s) PTO/SB/08A and/or B, which may be material to the patentability of this application and/or for which there may be a duty to disclose in accordance with 37 C.F.R. §1.56.

The enclosed references were cited in an International Search Report (copy enclosed) dated January 27, 2003 from the European Patent Office concerning counterpart International Application No. PCT/IT02/00370 and/or cited and discussed at pages 1-4 of the specification.

The filing of this Information Disclosure Statement shall not be construed as an admission that any of the listed documents constitutes prior art, nor as an admission against interest in any manner.

No fee is believed to be due in connection with the filing of this Information Disclosure Statement since it is being filed within three months of the filing date of the above-identified application. However, the Commissioner is hereby authorized to charge any deficiencies or credit any overpayments to Deposit Account No. 50-1017.

It is respectfully requested that this Information Disclosure Statement and the documents listed on the attached Form PTO/SB/08A and/or B be considered and acknowledged by the Examiner in connection with the above-identified patent application, be made of record therein, and that the listed document(s) be cited in the issued patent.

Respectfully submitted,

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November 24, 2003
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WWS:sm
Enclosures

Form PTO/SB/08A				Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT				**Application Number**	Not Yet Assigned
				Filing Date	Herewith
				First Named Inv nt r	Luca PUSTERLA, et al.
(use as many sheets as necessary)				**Group Art Unit**	Not Yet Assigned
				Examiner Nam	Not Yet Assigned
Sheet	1	of	1	**Attorney Docket Number**	6023-170US (BX2390M)

U.S. PATENT DOCUMENTS				
Exr Initials	U.S. Patent Document Number	Kind Code (if known)	Name of First Inventor of Cited Document	Date of Publication of Cited Document MM-YYYY
	5,558 844		SUCCI et al.	09-1996
	5,556,603		SUCCI et al.	09-1996
	5,457,316		COHEN et al.	10-1995
	5,955,886		COHEN et al.	09-1999
	4,551,624		SPANGLER et al.	11-1985
	5,032,721		BACON et al.	07-1991
	5,095,206		BACON et al.	03-1992
	5,238,199		OSSOINIG et al.	08-1993

FOREIGN PATENT DOCUMENTS						
Exr Initials	Foreign Patent Document Country Code	Number	Kind Code (if known)	Name of Applicant of Cited Document	Date of Publication of Cited Document MM-YYYY	T_1
	GB	2 177 079	A	Taiyo Sanso Co. Ltd.	01-1987	
	GB	2 177 080	A	Taiyo Sanso Co. Ltd.	01-1987	

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS		
Exr Initials	Include Name of first Author (in CAPITAL LETTERS), title of the article (where appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), volume-issue number(s), page(s), date (in parentheses). If a book, also include publisher and city and/or county where published.	T_1
	STIMAC et al., "Water Vapor Measurements In Small Volumes Using Atmospheric Pressure Chemical Ionization – Mass Spectrometry", *Proceedings of the Annual Symposium On Reliability Physics.*, Vol. Proc. 20, pp. 260-263, (1982)	
	STIMAC et al., "Use Of Ion Mobility Spectrometry To Determine Trace Level Impurities In Ultra High Purity Gases" *proceedings Institute Of Environmental Sciences*, pp. 5-12, (1996)	

Examiner Signature		Date Considered	